L Number	Hits	Search Text	DB	Time stamp
1	10495	inspect$4 near2 (semiconduct$3 or wafer or substrate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/04 10:53
8	629	(proposed or candidate) near defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/04 10:53
15	618	(actual or true) near defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/04 10:54
22	6	(inspect$4 near2 (semiconduct$3 or wafer or substrate)) and ((proposed or candidate) near defect) and ((actual or true) near defect)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2001/10/04 10:54

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